

FORM PTO-149 US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		App. Docket No. 86973RLO Customer No. 01333		Serial No. Not yet assigned 10/753,249	
If AFTER the later date of the first Office Action or 3 months from filing, use only with Rule 97(E) Certificate or Fee		Applicant: Kevin P. Klubek, et al.			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		Filing Date herewith 8 JAN 2004		Group Not yet assigned 1774	

U.S. PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DS	4,769,292	09-06-1988	Tang et al.	—	—	—
DS	5,908,581	06-01-1999	Chen et al.	—	—	—
DS	5,593,788	01-14-1997	Shi et al.	—	—	—
DS	5,141,671	08-25-1992	Bryan et al.	—	—	—
DS	6,582,837	06-24-2003	Toguchi et al.	—	—	—

FOREIGN PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
DS	11-273861	10-08-1999	Japan	—	—	X —
DS	2001-284050	10-12-2001	Japan	—	—	X —
DS	1 162 674 A2	05-28-2001	Europe	—	—	— —

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
DS	Dresner, RCA Review, 30, 332 (1969), pg. 322-334.
DS	Tang et al., Applied Physics Letters, 51, 913 (1987), p. 913-915.
DS	Tang et al., Journal of Applied Physics, 65, 3610 (1989), pg. 3610-3616.
DS	Popovic et al., Thin Solid Films 2000, 363, 6; SPIE 1998, 3476, 68 pg. 68-73.
DS	Hamada et al., Applied Phys. Lett. 75, 1682 (1999), pg. 1682-1684.
DS	U.S. Patent Application Publication 2003/0118866 A1 06/26/2003 Oh et al.

EXAMINER Raum Lefanett	DATE CONSIDERED April 27, 2006
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.